NALOG Product/Process Change Notice - PCN 19_0097 Rev. -

Analog Devices, Inc. Three Technology Way Norwood, Massachusetts 02062-9106

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

PCN Title: Data Sheet and Die Revision for AD9171/AD9172/AD9173

Publication Date: 25-Jun-2019

Effectivity Date: 27-Sep-2019 (the earliest date that a customer could expect to receive changed material)

Revision Description: Initial Release.

Description Of Change:

- 1. Added buffers to the direct clock path.
- 2. Clock redesign of the HB filters.
- 3. Improved digital layout.

4. Changed default value for SPI register 0x006 from value 0x2 to value 0x4. See "REGISTER SUMMARY" table in the relevant product data sheet.

Reason For Change:

- 1. Improve performance of the duty cycle control loop.
- 2. Reduces spurious levels at Fs/32, Fs/48, and Fs/64.
- 3. Digital layout re-synthesized due to change #2.
- 4. Indicates the die revision "4a" of the new material

Impact of the change (positive or negative) on fit, form, function & reliability:

- 1. Improves close-in Phase Noise performance, when using direct-clock mode.
- 2. Reduces spurious levels at Fs/32, Fs/48, and Fs/64. increases spurious levels at Fs/8, Fs/12, and Fs/16.
- 3. Improved power consumption on the DVDD1.0 supply domain.
- 4. SPI register value change. No impact otherwise

Product Identification (this section will describe how to identify the changed material)

SPI register read of register 0x006 shall return a value of 0x4.

Summary of Supporting Information:

Qualification has been performed per Industry Standard Test Methods. See attached Qualification Results Summary. Data Sheet changes will be reflected in revision B of the Product Data Sheet.

Supporting Documents

Attachment 1: Type: Qualification Results Summary

ADI_PCN_19_0097_Rev_- Qualification Results Summary_AD9171_AD9172_AD9173.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.								
Americas:	Europe:	Japan:	Rest of Asia:					
PCN_Americas@analog.com	PCN_Europe@analog.com	PCN_Japan@analog.com	PCN_ROA@analog.com					

Appendix A - Affected ADI Models							
Added Parts On This Revision - Product Family / Model Number (10)							
AD9171 / AD9171-FMC-FX3-EBZ	AD9171 / AD9171BBPZ	AD9171 / AD9171BBPZRL	AD9172 / AD9172BBPZ	AD9172 / AD9172BBPZRL			
AD9172/AD9172HUAWEI-DIE	AD9173/AD9173-FMC-FX3-EBZ	AD9173/AD9173-FX3-EBZ	AD9173/AD9173BBPZ	AD9173/AD9173BBPZRL			

Appendix B - Revision History					
Rev	Publish Date	Effectivity Date	Rev Description		
Rev	25-Jun-2019	27-Sep-2019	Initial Release.		

Analog Devices, Inc.

Docld:6708 Parent Docld:4664 Layout Rev:7

Die Revision for AD9171/AD9172/AD9173

Qualification Results Summary of AD9171/AD9172/AD9173 Die Revision

QUALIFICATION PLAN / STATUS					
TEST	SPECIFICATION	SAMPLE Size	RESULTS		
Solder Heat Resistance (SHR)*	JEDEC/IPC J-STD-020	1*30	Pass		
Latch-Up	JEDEC JESD78	1*9	Pass		
Electrostatic Discharge Human Body Model	ESDA/JEDEC JS-001	3/voltage	Pass ±500V		
Electrostatic Discharge Field-Induced Charged Device Model	JEDEC JS-002	3/voltage	Pass ±2000V		

*Preconditioned per JEDEC/IPC J-STD-020, MSL 3, Max Peak Reflow Temp of 260C